

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

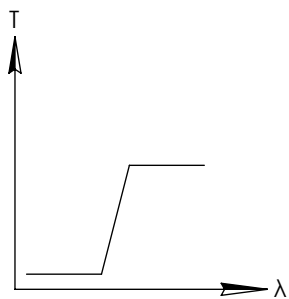
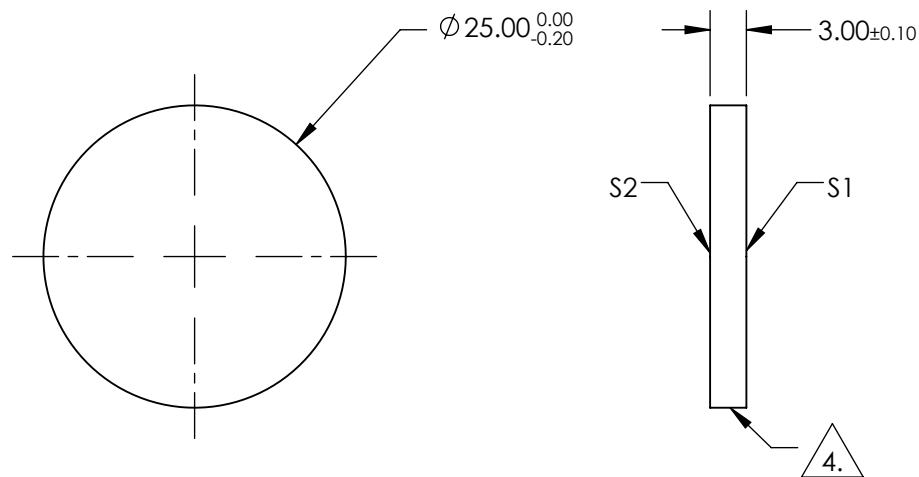
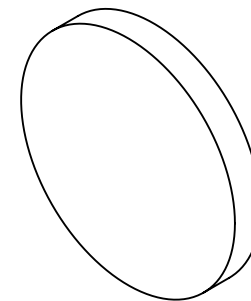
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 408 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 390nm @ 0° AOI  
 T(abs): =50% FOR 400±4nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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 DO NOT MANUFACTURE  
 PARTS TO THIS DRAWING**



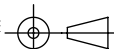
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 400nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62981

SHEET  
 1 OF 1

NOTES:

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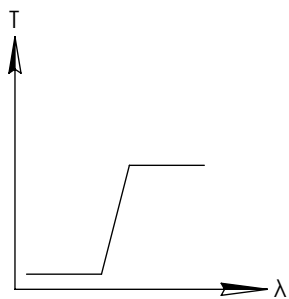
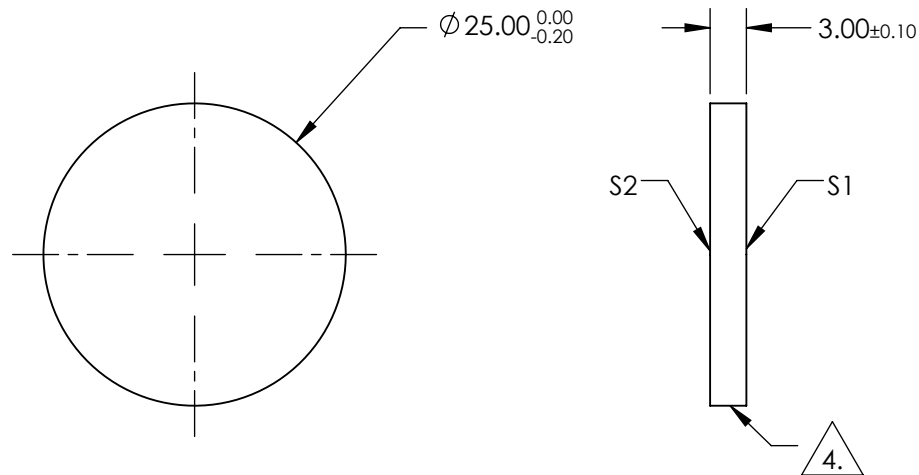
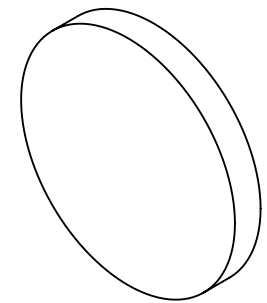
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 458 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 440nm @ 0° AOI  
 T(abs): =50% FOR 450±4.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



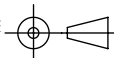
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 450nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62982

SHEET  
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

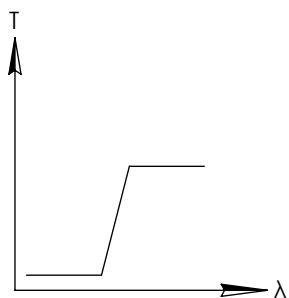
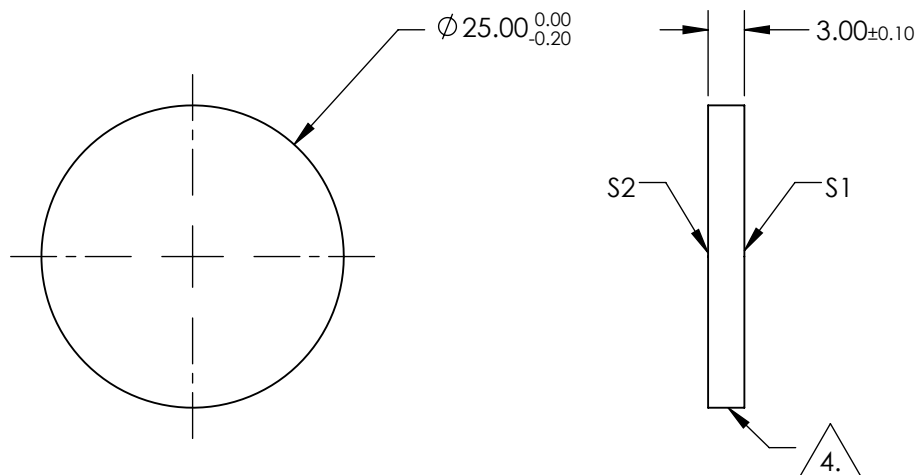
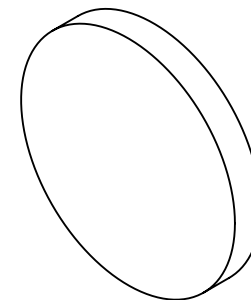
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 508 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 490nm @ 0° AOI  
 T(abs): =50% FOR 500±5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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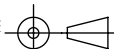
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 500nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62983

SHEET  
 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

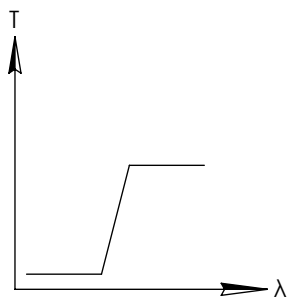
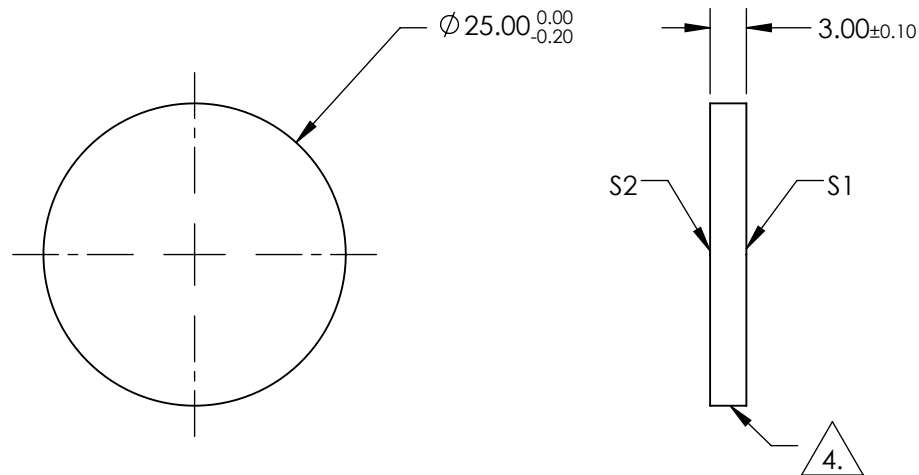
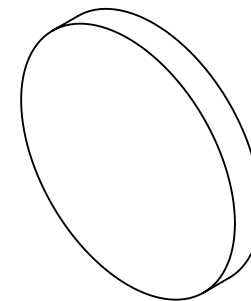
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 560 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 539nm @ 0° AOI  
 T(abs): =50% FOR 550±5.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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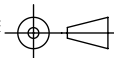
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 550nm, HIGH PERFORMANCE  
 LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62984

SHEET  
 1 OF 1

NOTES:

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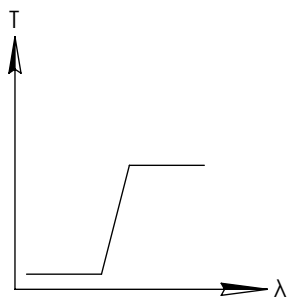
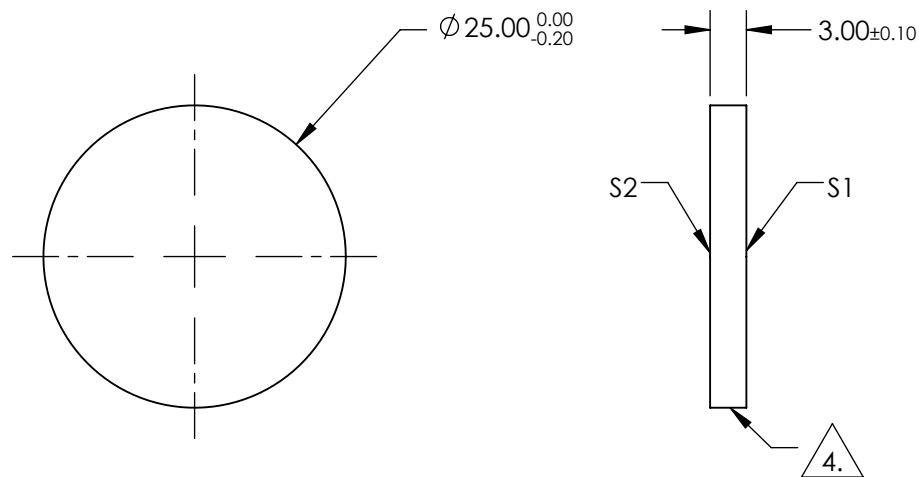
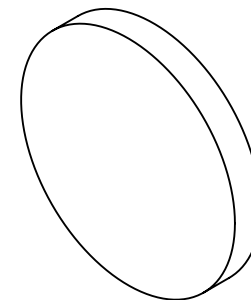
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 610 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 588nm @ 0° AOI  
 T(abs): =50% FOR 600±6nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



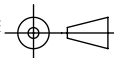
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 600nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62985

SHEET  
1 OF 1

NOTES:

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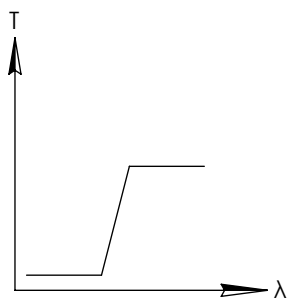
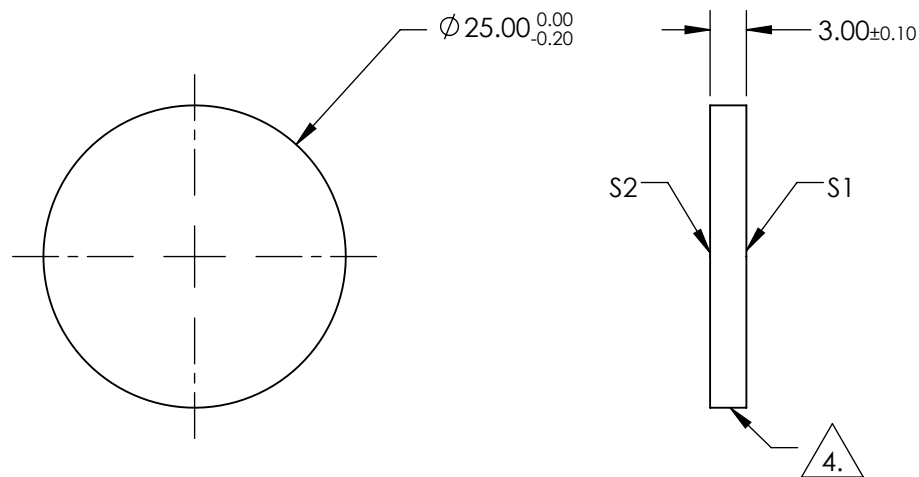
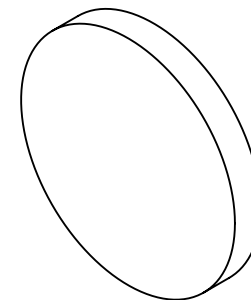
1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 660 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 637nm @ 0° AOI  
 T(abs): =50% FOR 650±6.5nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT



LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
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REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE PROJECTION

ALL DIMS IN mm

TITLE	Ø25mm, 650nm, HIGH PERFORMANCE LONGPASS FILTER		
DWG NO	62986	SHEET	1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

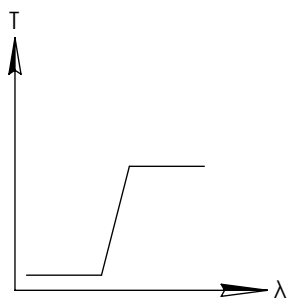
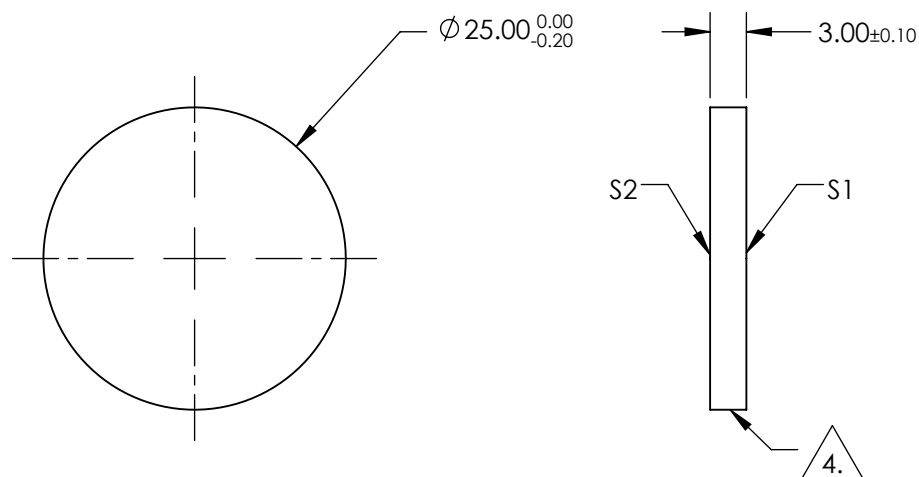
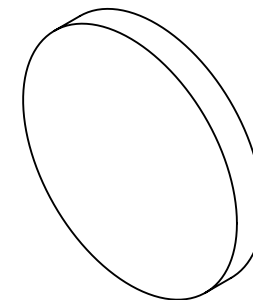
S1: HARD DIELECTRIC SPUTTERED  
 T(avg): ≥91% FROM 710 - 1650nm @ 0° AOI  
 T(avg): ≤0.01% FROM 200 - 686nm @ 0° AOI  
 T(abs): =50% FOR 700±7nm @ 0° AOI

S2: SINGLE LAYER MgF2

4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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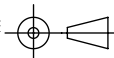
LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
 DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

**EO**® Edmund Optics®

THIRD ANGLE PROJECTION



TITLE

Ø25mm, 700nm, HIGH PERFORMANCE  
LONGPASS FILTER

ALL DIMS IN

mm

DWG NO

62987

SHEET  
1 OF 1